

Supporting Information for
**In-intercalation and Si-containing protective layer enhance
electrochemical performance of $\text{NaNi}_{0.5}\text{Mn}_{0.5}\text{O}_2$ for sodium-ion
batteries**

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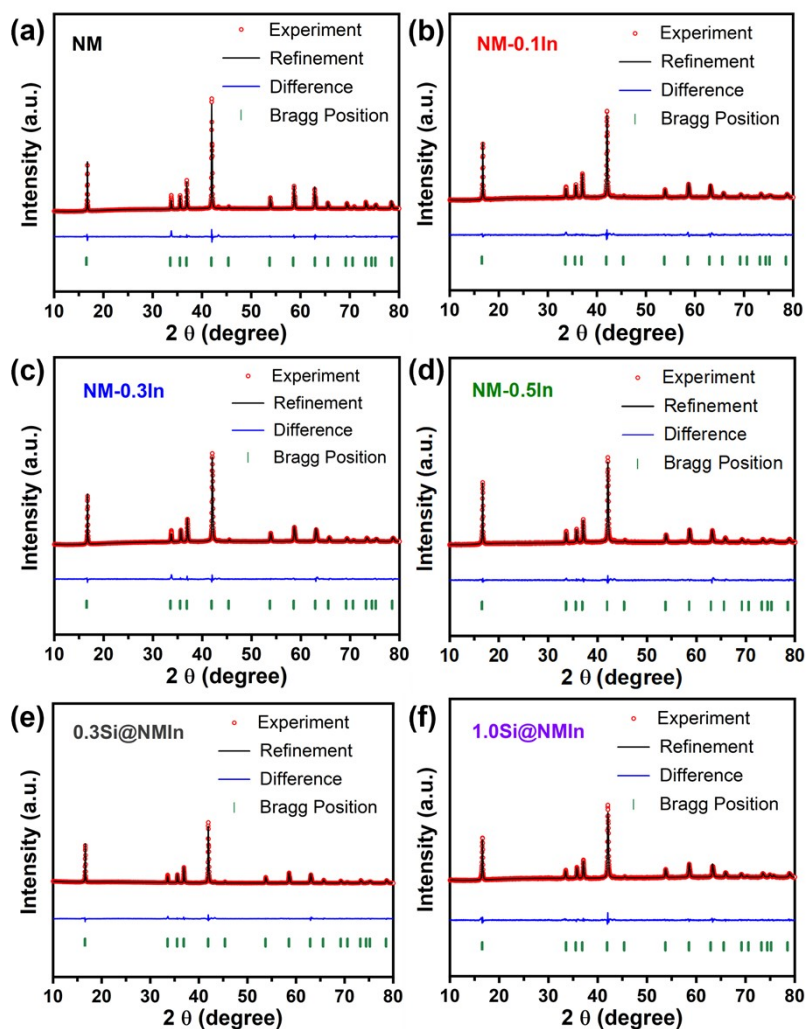


Fig. S1 Rietveld refinement profiles of (a) NM, (b-d) modified with different In contents intercalation and (e, f) Si@In-doping samples.

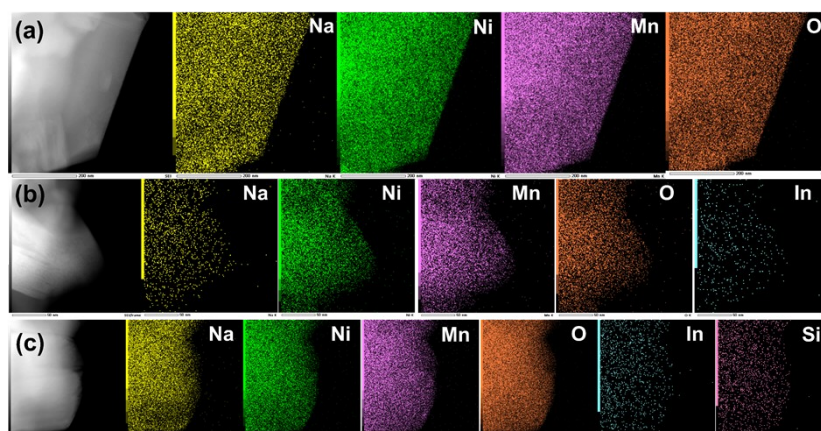


Fig. S2 TEM elemental mappings of Na, O, Mn, Ni, In and Si of (a) NM, (b) NM-0.3In and (c) 0.5Si@NMIn

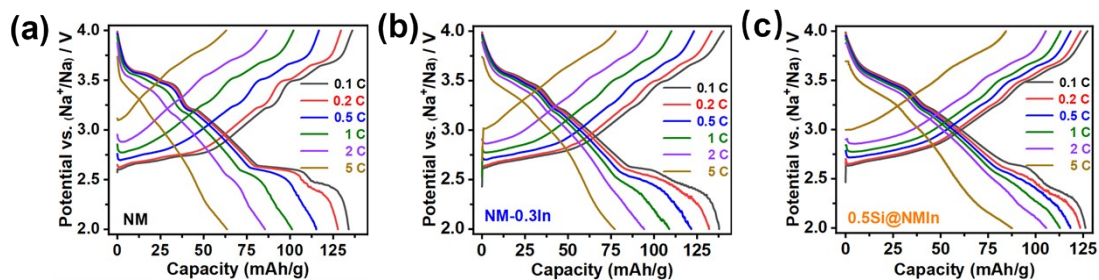


Fig. S3 The charge-discharge curves of (a) the NM55, (b) the NM-0.3In and (c) the 0.5Si@NMIn at 2.0-4.0 V and 25 °C under different rates.

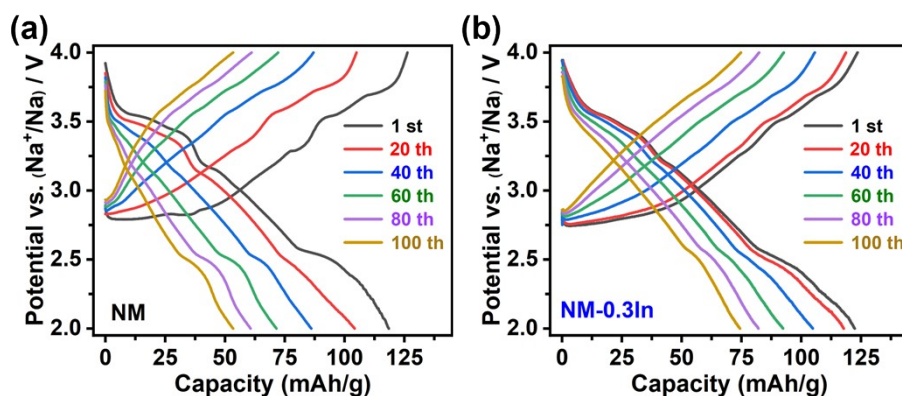


Fig. S4 The galvanostatic charge-discharge (GCD) curves of (a) NM, (b) NM-0.3In.

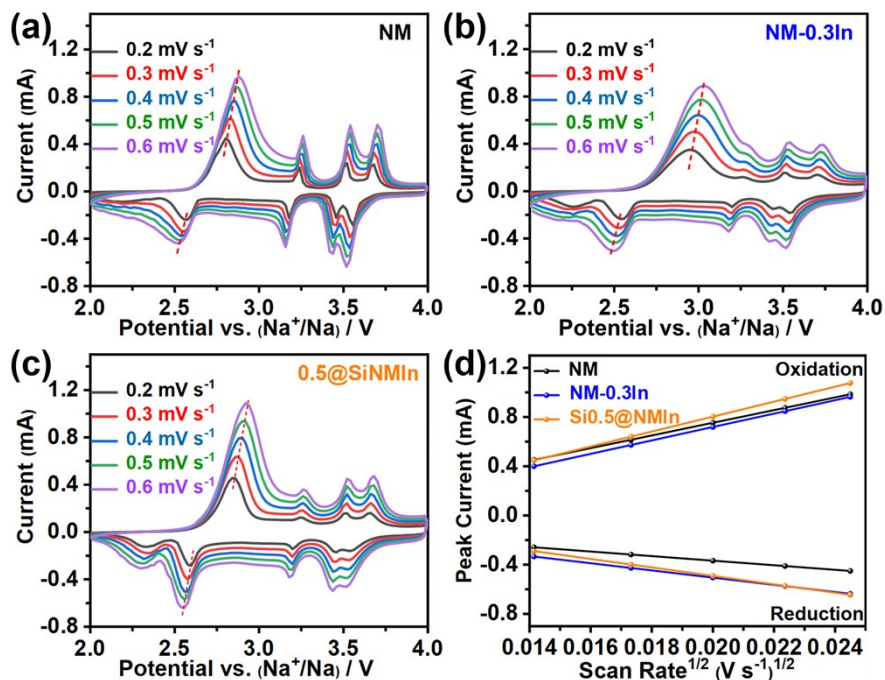


Fig. S5 CV tests of (a) NM, (b) NM-0.3In and (c) 0.5Si@NMIn at the different scan rates. (d) The linear fitting of the peak currents of oxidation/reduction peaks at different scan rates with the square root of the scan rates.

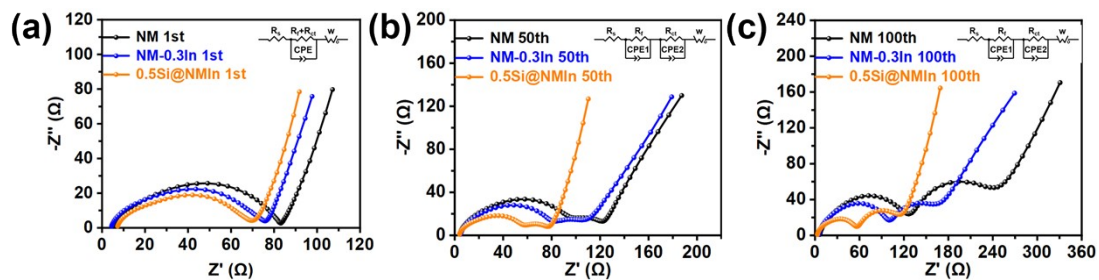


Fig. S6 The Nyquist plots of NM, NMIn-0.3 and 0.5Si@NMIn cathodes in the (a) 1st, (b) 50th and (c) 100th over 2.0-4.0 V.

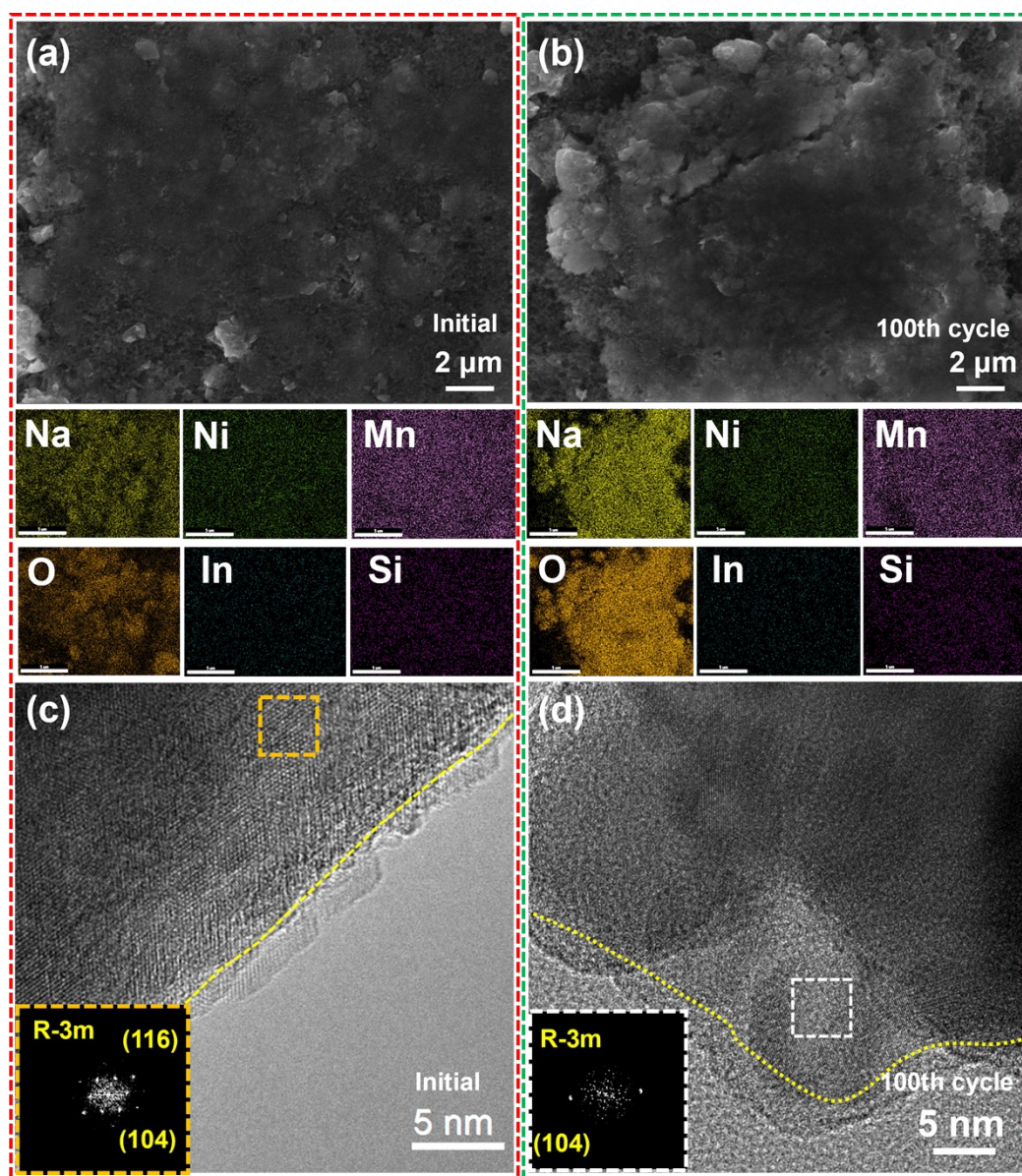


Fig. S7 SEM images of (a) the initial pole piece of 0.5Si@NMIn and (b) the spent pole piece of 0.5Si@NMIn experienced 100 cycles at 1 C. TEM images of (c) the fresh 0.5Si@NMIn and (d) the spent 0.5Si@NMIn experienced 100 cycles at 1 C.

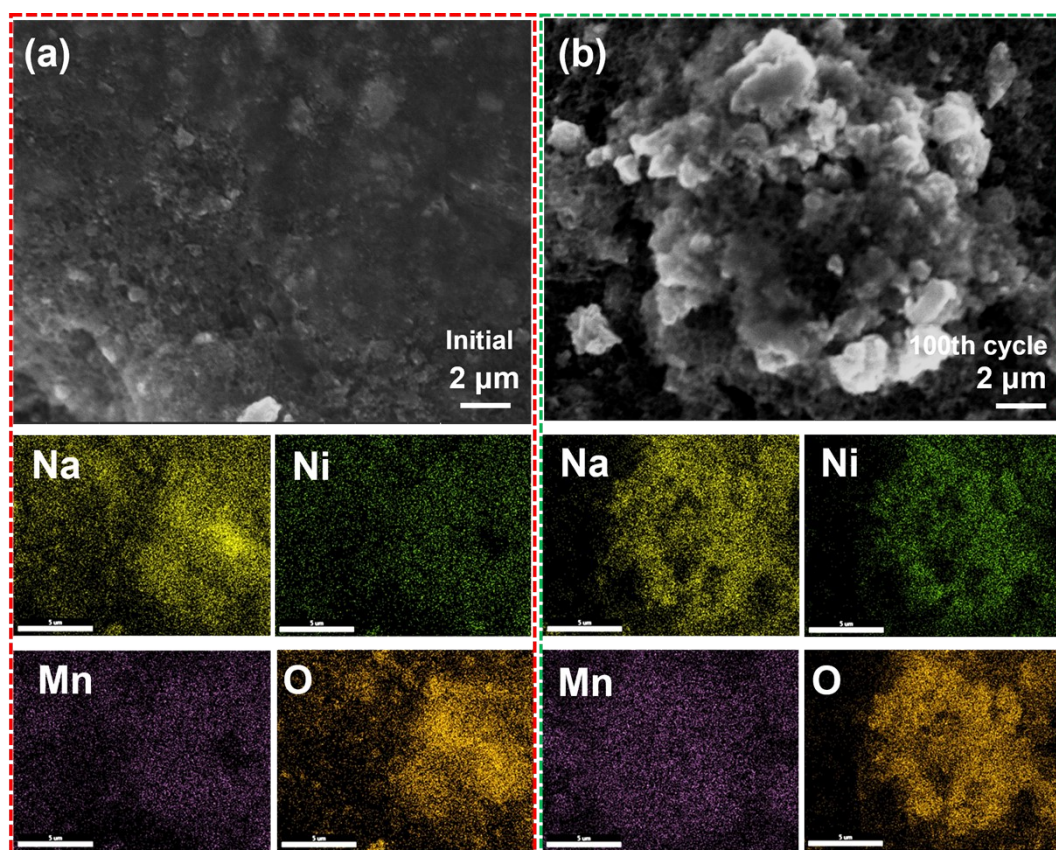


Fig. S8 SEM images of (a) the initial pole specie of NM and (b) the spent pole specie of NM experienced 100 cycles at 1 C.

Table S1 Relative percentages and binding energies of $\text{Ni}^{2+}/\text{Ni}^{3+}$ in Ni 2p XPS spectra.

Sample	Ni 2p _{3/2} (eV)		Ni 2p _{1/2} (eV)		Ni content (%)	
	Ni ²⁺	Ni ³⁺	Ni ²⁺	Ni ³⁺	Ni ²⁺	Ni ³⁺
NM	854.46	856.15	871.91	873.72	82.60	17.40
NM-0.3In	854.56	856.25	872.11	874.55	79.38	20.62
0.5Si@NMIn	854.79	856.58	872.42	874.65	75.65	24.35

Table S2 Relative percentages and binding energies of $\text{Mn}^{3+}/\text{Mn}^{4+}$ in Mn 2p XPS spectra.

Sample	Mn 2p _{3/2} (eV)		Mn 2p _{1/2} (eV)		Mn content (%)	
	Mn ³⁺	Mn ⁴⁺	Mn ³⁺	Mn ⁴⁺	Mn ³⁺	Mn ⁴⁺
NM	641.53	643.50	652.49	653.79	65.90	34.10
NM-0.3In	641.62	643.52	653.08	653.96	59.68	40.32
0.5Si@NMIn	641.85	643.66	653.03	654.01	57.37	42.63

Table S3 Relative percentages and binding energies of oxygen species in O 1s XPS spectra.

Sample	Adsorbed O		O Vacancy		Lattice O	
	O 1s	O	O 1s	O	O 1s	O
	(eV)	content (%)	(eV)	content (%)	(eV)	content (%)
NM	528.75	11.18	530.93	77.98	535.27	10.84
NM-0.3In	528.81	9.95	530.98	79.16	535.31	10.89
0.5Si@NMIn	529.43	8.51	531.22	78.51	535.66	12.98

Table S4 Na⁺ diffusion coefficient (D_{Na^+}) of NM, NM-0.3In and 0.5Si@NMIn.

Sample	D_{Na^+} (cm ² s ⁻¹)	
	Desodiation	Sodiation
NM	3.48×10^{-11}	4.55×10^{-12}
NM-0.3In	3.65×10^{-11}	8.90×10^{-12}
0.5Si@NMIn	4.76×10^{-11}	1.12×10^{-11}

Table S5 EIS fitting results of NM, NM-0.3In and 0.5Si@NMIn.

Sample	Cycle	R_s (Ω)	$R_f + R_{ct}$ (Ω)
NM	1 st	4.14	80.82
	50 th	2.93	128.45
	100 th	5.08	265.4
NM-0.3In	1 st	3.63	69.7
	50 th	3.42	118.38
	100 th	3.58	170.22
0.5Si@NMIn	1 st	6.15	63.78
	50 th	3.15	97.20
	100 th	1.86	124.87

Table S6 Resistivity and conductivity results of NM, NM-0.3In and 0.5Si@NMIn.

Sample	Pressure (Mpa)	Resistivity (kΩ m)	Conductivity (S m ⁻¹)
NM	2	30.70	3.26×10 ⁻⁵
	3	28.85	3.47×10 ⁻⁵
	4	27.05	3.70×10 ⁻⁵
NM-0.3In	2	27.91	3.58×10 ⁻⁵
	3	26.02	3.84×10 ⁻⁵
	4	24.11	4.15×10 ⁻⁵
0.5Si@NMIn	2	22.98	4.35×10 ⁻⁵
	3	20.87	4.79×10 ⁻⁵
	4	18.91	5.29×10 ⁻⁵

Galvanostatic intermittent titration technique (GITT) measurement in the 1st cycle and 100th cycle are utilized to determine the Na⁺ diffusion coefficient (D_{Na^+}) within NM, NM-0.3In and 0.5Si@NMIn cathodes. The D_{Na^+} value can be derived using the following formula:

$$D_{\text{Na}^+} = \frac{4}{\pi\tau} \left(\frac{m_B V_M}{M_B A} \right)^2 \left(\frac{\Delta E_S}{\Delta E_\tau} \right)^2 \quad (\text{S1})$$

Where τ (s) represents the galvanostatic current pulse time, V_M , M_B , and m_B are the molar volume (obtained from the Rietveld refinement results from GSAS II), molecular weight, and the molar mass of the active material, respectively. Meanwhile, A signifies the electrode surface area, ΔE_τ and ΔE_S is the voltage change during the constant current pulse and the corresponding relaxation process.